



PCM-5335

Temperature cycle Test Report

Report NO : 02E020031

Issued by:

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10/11/2002

Rex Chang
QE Engineer

Date

Reviewed by:

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10/11/2002

Lindon-Liu
QE Manager

Date

PCM-5535

Test Date: 10-07~10-11-2002

Test Product: PCM-5335 (PCB Rev:B0.1 BIOS Rev:B0.1)

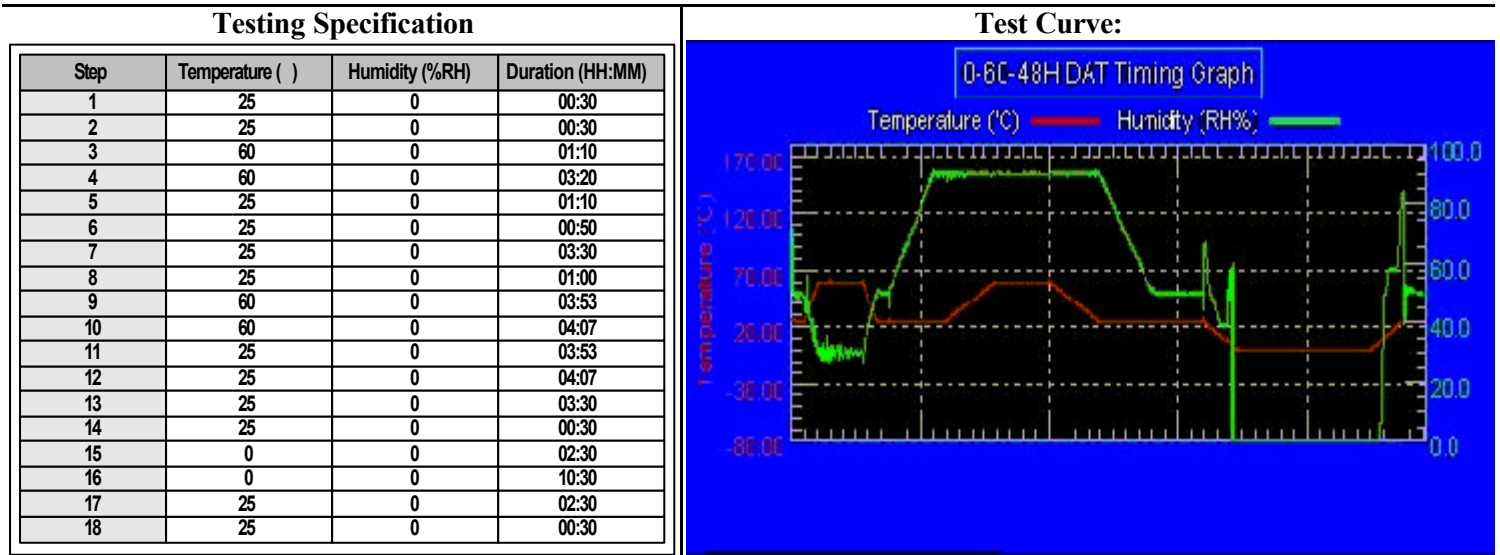
Test Site: AAEON QA Internal Lab.

Performed By : Rex Chang

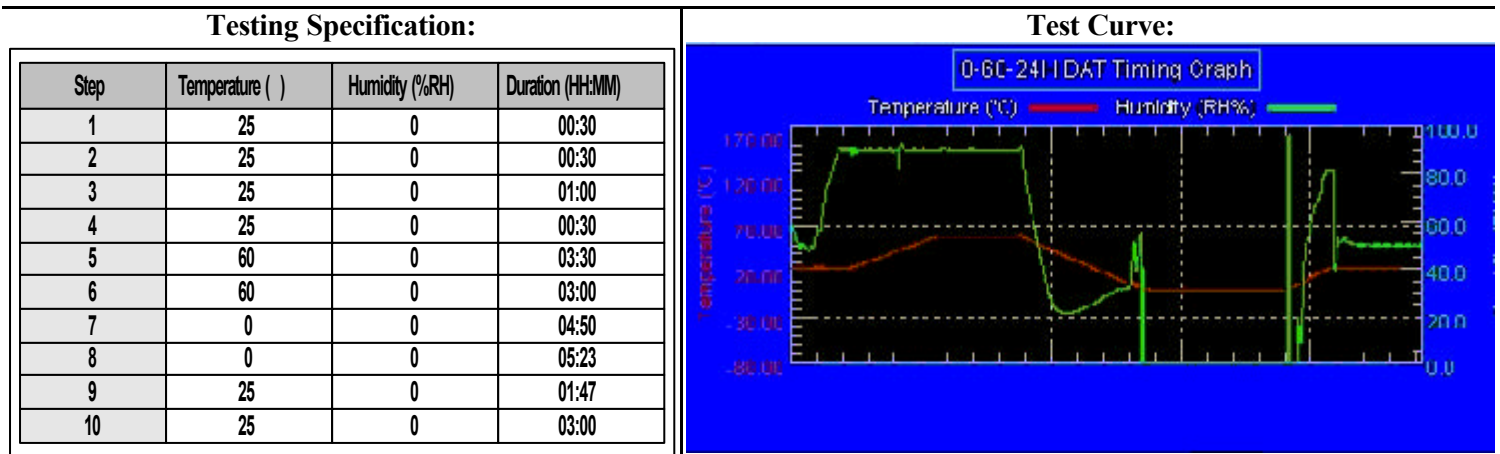
Test Standard : Reference IEC 68-2-30 Testing procedures
 Test DB : Damp Heat Test
 Reference IEC 68-2-61 Testing procedures
 Test Z/ABD : Climatic Sequence Test

Test Equipment:
 Programmable Temperature & Humidity Chamber
 K.SON. INS. TECH. CORP.
 Model : THS-D4H+-100
 Date of Calibration : 06/10/01
 Serial Number: 1241

Temperature & Humidity Cycle Test:



Temperature & Humidity Power On/Off Test



Sample Configuration & Quantity Under Test:

1. CPU : Embedded Low power NS Geode GX1-300 MHz processor
2. SDRAM : NEC 128M D45128163G5 SO-DIMM(PC100)
3. VGA : NS CS5530A 1 ~ 4 MB share memory, set in BIOS
4. LAN : Realtek RTL8139DL (100-pin LQFP)

Test Result :

Passed.

The PCM-5335 compact board meets temperature cycle test.